Docket #: S13-388

Fast Quick Error Detection (Fast QED) Tests

Stanford researchers have developed new Fast Quick Error Detection (Fast QED) tests that are four orders of magnitude faster than standard QED tests while also preserving quick error detection properties. Fast QED tests are highly effective and significantly reduce runtime when compared to existing non-QED or non-QED-RR post-silicon validations.

Technology operates in combination with **Stanford Docket S14-456**

Publications

- *Quick Error Detection Tests with Fast Runtimes for Effective Post-Silicon Validation and Debug*

Patents

- Published Application: 20150377961
- Issued: 9,928,150 (USA)

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